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October 2014

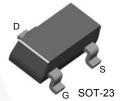
BSS138L N-Channel Logic Level Enhancement Mode Field Effect Transistor

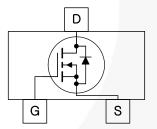
Features

- High Density Cell Design for Low R_{DS(ON)}
- · Rugged and Reliable
- Compact Industry Standard SOT-23 Surface Mount Package
- · Very Low Capacitance
- · Fast Switching Speed

Description

This N-channel enhancement mode field effect transistor is produced using high cell density, trench MOSFET technology. This product minimizes on-state resistance while providing rugged, reliable, and fast switching performance. This product is particularly suited for low-voltage, low-current applications such as small servo motor control, power MOSFET gate drivers, logic level translator, high speed line drivers, power management/power supply and switching applications.





Ordering Information

Part Number	Marking	Package	Packing Method	
BSS138L	SL	SOT-23 3L	Tape and Reel	

1

Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only. Values are at $T_A = 25$ °C unless otherwise noted.

Symbol	Parameter		Value	Unit	
V _{DSS}	Drain-Source Voltage		50	V	
V _{GSS}	Gate-Source Voltage		±20	V	
I _D	Maximum Drain Current	Continuous	0.20	А	
		Pulsed	0.80		
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
T _L	Maximum Lead Temperature for Soldering Purposes, 1/16 inch from Case for 10 Seconds		300	°C	

Thermal Characteristics

Values are at T_A = 25°C unless otherwise noted.

Symbol	Parameter	Value	Unit
P _D	Maximum Power Dissipation ⁽¹⁾	0.35	W
	Derate Above 25°C	2.8	mW/°C
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient ⁽¹⁾	380	°C/W

Note:

1. $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 380°C/W when mounted on a minimum pad.

Scale 1: 1 on letter size paper

ESD Rating(2)

Symbol	Parameter	Value	Unit
HBM	Human Body Model per ANSI/ESDA/JEDEC JS-001-2012 50		V
CDM	Charged Device Model per JEDEC C101C	>2000	

Note:

2. ESD values are in typical, no over-voltage rating is implied, ESD CDM zap voltage is 2000 V maximum.

Electrical Characteristics

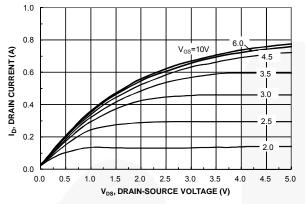
Values are at $T_A = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Charac	teristics			•		•
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	50.0	65.4		V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		58		mV/°C
I _{DSS}		V _{DS} = 50 V, V _{GS} = 0 V		0.263	500	nA
	Zero Gate Voltage Drain Current	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V},$ $T_{J} = 125^{\circ}\text{C}$		0.109	5	μΑ
		V _{DS} = 30 V, V _{GS} = 0 V		0.062	100	nA
I _{GSSF}	Gate-Body Leakage, Forward	V _{GS} = 20 V, V _{DS} = 0 V		0.058	100	~ A
I _{GSSR}	Gate-Body Leakage, Reverse	V _{GS} = -20 V, V _{DS} = 0 V		-0.06	-100	- nA
On Charac	teristics ⁽³⁾			•		
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 1 \text{ mA}$	0.80	1.25	1.50	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I _D = 1 mA, Referenced to 25°C		-2.42		mV/°C
В	Static Drain-Source	V _{GS} = 5 V, I _D = 0.20 A		2.78	3.50	
R _{DS(ON)}	On-Resistance	V _{GS} = 2.75 V, I _D = 0.20 A		3.78	10	Ω
I _{D(ON)}	On-State Drain Current	V _{GS} = 10 V, V _{DS} = 5 V	0.20	0.67		Α
9 _{FS}	Forward Transconductance	V _{DS} = 10 V, I _D = 0.22 A	0.12	0.35		S
Dynamic C	Characteristics					
C _{iss}	Input Capacitance			12.2	50	pF
C _{oss}	Output Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		3.04	25	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1.0 WH 12		1.43	5	pF
R_{G}	Gate Resistance	V _{GS} = 15 V, V _{GS} = 1.0 MHz		26.6		Ω
Switching	Characteristics ⁽³⁾				•	
t _{d(on)}	Turn-On Delay			2.2	5	ns
t _r	Turn-On Rise Time	V _{DD} = 30 V, I _D = 0.29 A,	- /	1.8	18	ns
t _{d(off)}	Turn-Off Delay	V _{GS} = 10 V		5.3	36	ns
t _f	Turn-Off Fall Time			5.1	14	ns
Qg	Total Gate Charge	V _{DS} = 25 V, I _D = 0.22 A, V _{GS} = 10 V, I _G = 0.1 mA		0.549	2.4	nC
Q _{gs}	Gate-Source Charge			0.075		nC
Q _{gd}	Gate-Drain Charge	VGS 10 V, 1G 0.1 11//		0.117		nC
Drain-Sour	ce Diode Characteristics and Ma	ximum Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				0.22	Α
V_{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 115 mA		0.93	1.4	V

Note:

3. Pulse test: pulse width \leq 300 μ s, duty cycle \leq 2.0%.

Typical Performance Characteristics



3.0

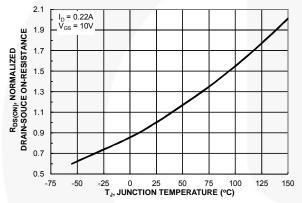
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Figure 1. On-Region Characteristics

Figure 2. On-Resistance Variation with Gate Voltage and Drain Current



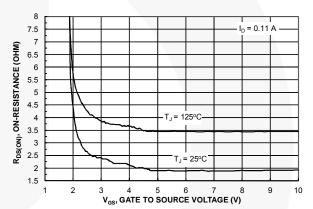
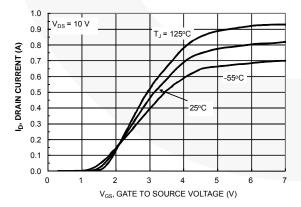


Figure 3. On-Resistance Variation with Temperature

Figure 4. On-Resistance Variation with Gate-to-Source Voltage



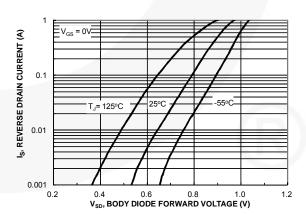
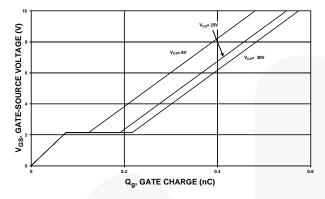


Figure 5. Transfer Characteristics

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature

Typical Performance Characteristics (Continued)



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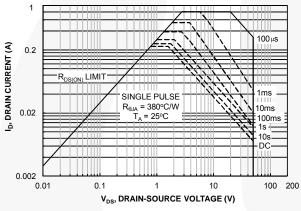
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V_{os}, DRAIN TO SOURCE VOLTAGE (V)

Figure 7. Gate Charge Characteristics

Figure 8. Capacitance Characteristics



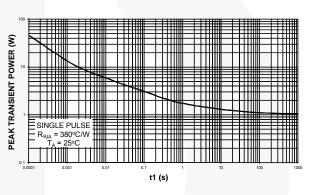


Figure 9. Maximum Safe Operating Area

Figure 10. Single Pulse Maximum Power Dissipation

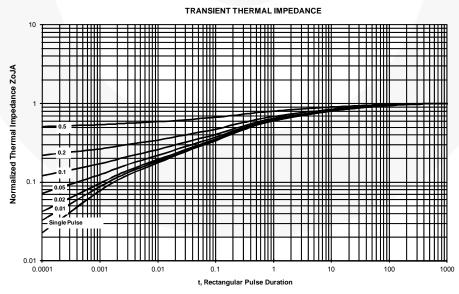
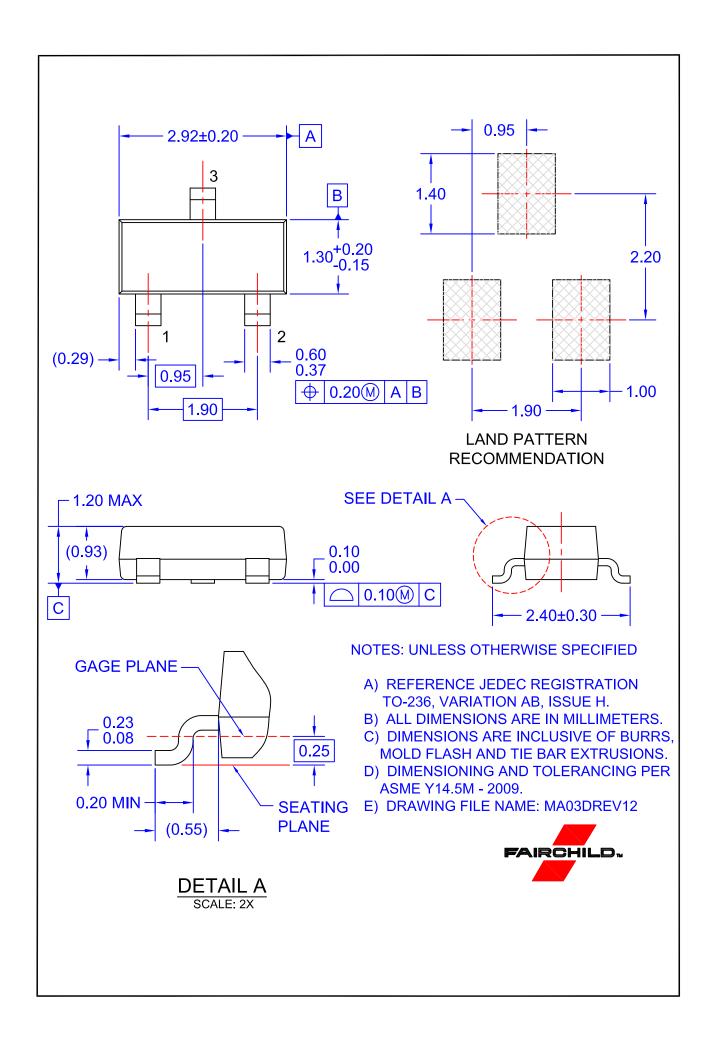


Figure 11. Transient Thermal Response Curve.



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